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Assembly Site	t Shipp	ing Label (not actua	al product label)	
Amkor P3	Asse	mbly Site Origin (22L)	ASO: AP3	ECAT:G3
Amkor P3	Asse	mbly Site Origin (22L)	ASO: AP3	ECAT:G4
TEXAS	(			actual product label)
TEXAS INSTRUMENTS MADE IN: Malaysi 2DC: 22: MSL 2 /260C/1 YEL MSL 1 /235C/UNLIN OPT: ITEM: LBL: 5A (L) Product Affected	AR SEAL 0 M 03/29/ T0:175		(1P) SN74LS07NSR (Q) 2000 (D) 033 (31T) LOT: 3959047ML (4W) TKY (1T) 7523483 (P) (2P) REV: (V) 0033: (20L) CSO: SHE (21L) CCO: (22L) ASO: MLA (23L) ACO:	6 ISI2
2DC: 2d: MSL '2 /260C/1 YE/ MSL 1 /235C/UNLIN OPT: ITEM: LBL: 5A (L)	a AR SEAL 0 03/29/ TO:175		(1P) SN74LS07NSR (Q) 2000 (D) 033 (31T) LOT: 3959047ML (4W) TKY (1T) 7523483 (P) (2P) REV: (V) 00333 (20L) CSO: SHE (21L) CCO:	6 ISI2

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com